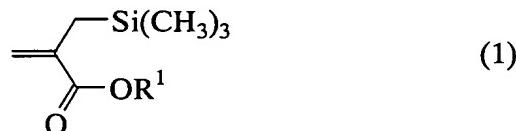


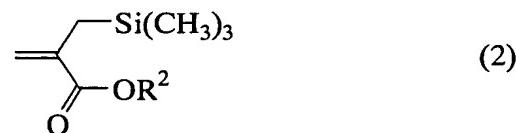
**CLAIMS:**

1. A polymerizable silicon-containing compound having the general formula (1):



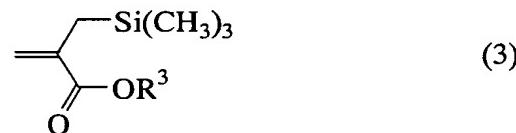
wherein R<sup>1</sup> is a hydrogen atom, halogen atom or monovalent organic group.

10 2. A polymerizable silicon-containing ester derivative having an acid eliminatable substituent group according to claim 1, having the general formula (2):



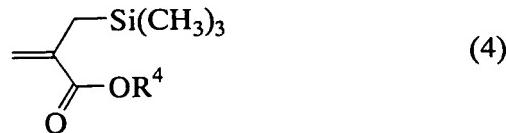
wherein R<sup>2</sup> is an acid labile group.

15 3. A polymerizable silicon-containing ester derivative having a polar group according to claim 1, having the general formula (3):



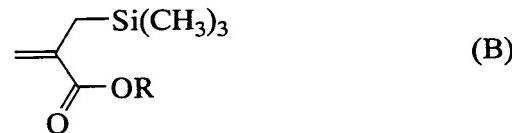
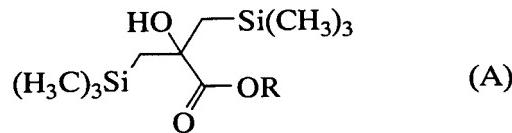
wherein R<sup>3</sup> is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group such as hydroxyl, carbonyl, ether bond or ester bond.

4. A polymerizable silicon-containing ester derivative having a silicon-containing group according to claim 1, having the general formula (4):



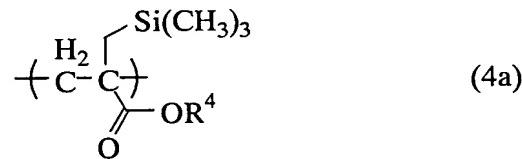
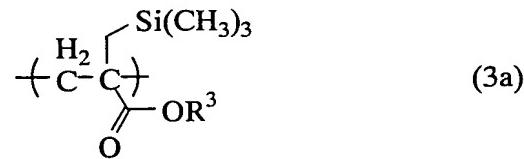
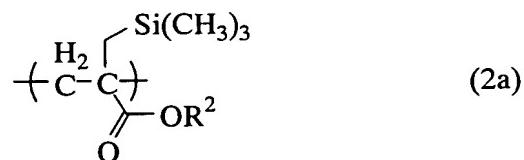
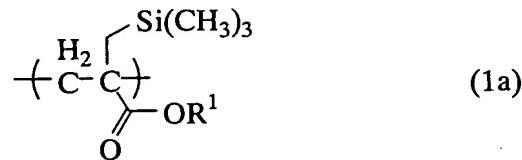
5 wherein R<sup>4</sup> is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

5. A method for preparing a polymerizable silicon-containing compound having the general formula (B), comprising the steps of reacting an oxalate with a trimethylsilylmethyl-metal compound to form a β-hydroxysilyl compound having the general formula (A) and subjecting the β-hydroxysilyl compound to Peterson elimination reaction,



15 wherein R stands for R<sup>1</sup>, R<sup>2</sup>, R<sup>3</sup> or R<sup>4</sup>, R<sup>1</sup> is a hydrogen atom, halogen atom or monovalent organic group, R<sup>2</sup> is an acid labile group, R<sup>3</sup> is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and R<sup>4</sup> is a monovalent organic group of 3 to 30 carbon atoms containing 20 at least one silicon atom.

6. A polymer comprising recurring units of the general formula (1a), (2a), (3a) or (4a) and having a weight average molecular weight of 2,000 to 100,000,



5 wherein R<sup>1</sup> is a hydrogen atom, halogen atom or monovalent organic group, R<sup>2</sup> is an acid labile group, R<sup>3</sup> is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and R<sup>4</sup> is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

7. The polymer of claim 6 further comprising recurring units of at least one type having the general formula (5a) or (6a):



5 wherein  $Y^1$ ,  $Y^2$ ,  $Y^3$  and  $Y^4$  are each independently selected from the group consisting of hydrogen, alkyl groups, aryl groups, halogen atoms, alkoxy carbonyl groups, alkoxy carbonylmethyl groups, cyano groups, fluorinated alkyl groups, and silicon atom-containing monovalent organic groups of 3 to 30 carbon atoms, any two of  $Y^1$ ,  $Y^2$ ,  $Y^3$  and  $Y^4$  may bond together to form  
10 a ring, Z is an oxygen atom or  $NR^5$ , and  $R^5$  is hydrogen, hydroxyl or alkyl.

8. A resist composition comprising the polymer of claim 6.

15

9. A chemically amplified positive resist composition comprising

- (A) the polymer of claim 6,
- (B) a photoacid generator, and
- 20 (C) an organic solvent.

10. A method for forming a pattern, comprising the steps of:

25 applying the positive resist composition of claim 9 onto an organic film on a substrate to form a coating,  
prebaking the coating to form a resist film,  
exposing a circuitry pattern region of the resist film to radiation,  
post-exposure baking the resist film,

developing the resist film with an aqueous alkaline solution to dissolve away the exposed area, thereby forming a resist pattern, and

5 processing the organic film with an oxygen plasma generated by a dry etching apparatus.